



ELECTRICAL CHARACTERISTICS (T<sub>j</sub>=25 unless otherwise specified)

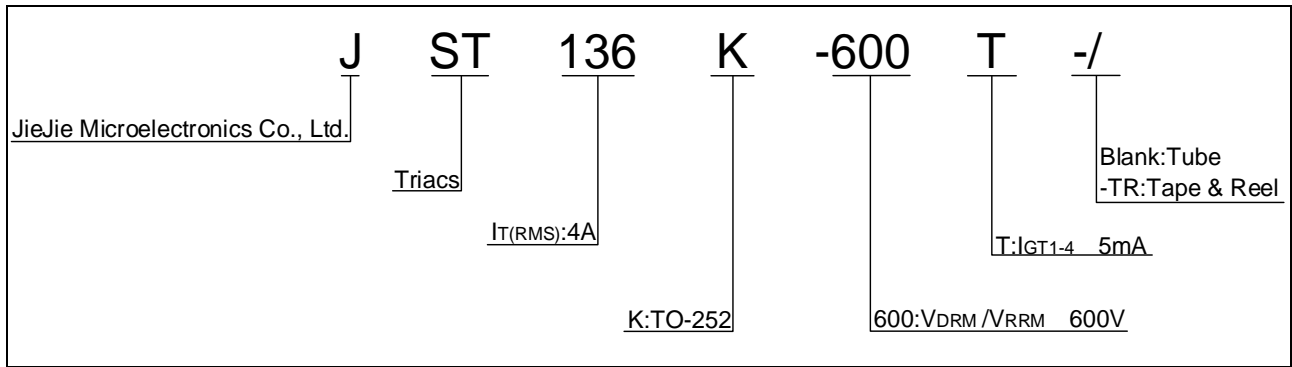
Symbol	Test Condition	Quadrant	Value		Unit
I <sub>GT</sub>	V <sub>D</sub> =12V R <sub>L</sub> =33	ALL	MAX.	5	mA
V <sub>GT</sub>		ALL	MAX.	1	V
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> T <sub>j</sub> =125 R <sub>L</sub> =3.3k	ALL	MIN.	0.2	V
I <sub>L</sub>	I <sub>G</sub> =1.2I <sub>GT</sub>	-	MAX.	10	mA
		-		15	
I <sub>H</sub>	I <sub>T</sub> =100mA		MAX.	5	mA
dV/dt	V <sub>D</sub> =400V Gate Open T <sub>j</sub> =110		MIN.	30	V/μs
(dV/dt) <sub>c</sub>	(dI/dt) <sub>c</sub> =1.8A/ms, T <sub>j</sub> =110		MIN.	1	V/μs
t <sub>on</sub>	I <sub>G</sub> =10mA I <sub>A</sub> =200mA I <sub>R</sub> =20mA T <sub>j</sub> =25		TYP.	1	μs
t <sub>off</sub>				12	

STATIC CHARACTERISTICS

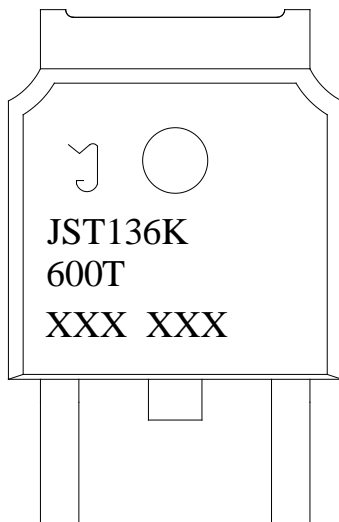
Symbol	Parameter		Value(MAX.)	Unit
V <sub>TM</sub>	I <sub>TM</sub> =5A t <sub>p</sub> =380μs	T <sub>j</sub> =25	1.7	V

V<sub>TO</sub> Threshold voltage T<sub>j</sub>=125 1. 933.2 0.48 0.481 re f 390 4

## ORDERING INFORMATION



## MARKING



**JST136K-600T**

**FIG.7:** Relative variations of gate trigger current, holding current and latching current versus junction temperature

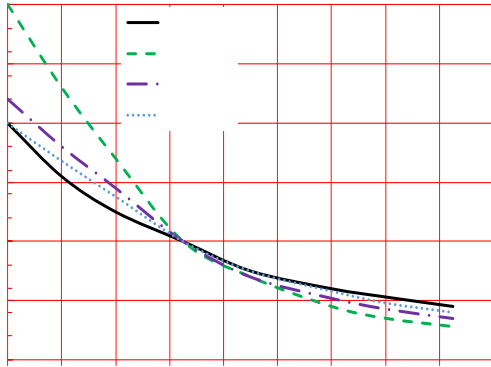


FIG.8 Test circuit for inductive and resistive loads to

**ORDERING INFO**





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